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- ☐ Standards

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- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

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- ☐ Conference Proceedings
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- ☐ Basic
- ☐ Advanced
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- ☐ Basic
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 pointing <near/3> error In:

 And

 spindle <near/3> position In:

 And
 In:

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- ☐ By Author
- ☐ Basic
- ☐ Advanced
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pointing <near/3> error<and>spindle <near/3> posit

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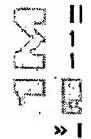
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- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

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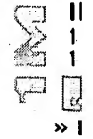
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Tables of Contents

- ☐ Journals & Magazines
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- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
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Tables of Contents

- ☐ Journals & Magazines
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- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
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ASSP Magazine, IEEE [see also IEEE Signal Processing Magazine] , Volume: 3 , Issue: 4 , Oct 1986

Pages:18 - 28

[\[Abstract\]](#) [\[PDF Full-Text \(1472 KB\)\]](#) **IEEE JNL****2 A heuristic description of generalized matrix inversion***Eisemann, K.;*

Circuits and Systems, IEEE Transactions on [legacy, pre - 1988] , Volume: 20 , Issue: 5 , Sep 1973

Pages:481 - 487

[\[Abstract\]](#) [\[PDF Full-Text \(86 KB\)\]](#) **IEEE JNL****3 On the time-bandwidth concentration of signal functions forming geometric vector configurations***Dollard, P.;*

Information Theory, IEEE Transactions on , Volume: 10 , Issue: 4 , Oct 1964

Pages:328 - 338

[\[Abstract\]](#) [\[PDF Full-Text \(1816 KB\)\]](#) **IEEE JNL****4 A stochastic geometrical vector model of macro- and megacellular communication channels***Oestges, C.;*

Vehicular Technology, IEEE Transactions on , Volume: 51 , Issue: 6 , Nov. 2002

Pages:1352 - 1360

[\[Abstract\]](#) [\[PDF Full-Text \(455 KB\)\]](#) [IEEE JNL](#)

5 Performance bounds for estimating vector systems

Nehorai, A.; Hawkes, M.;

Signal Processing, IEEE Transactions on [see also Acoustics, Speech, and Signal Processing, IEEE Transactions on] , Volume: 48 , Issue: 6 , June 2000

Pages:1737 - 1749

[\[Abstract\]](#) [\[PDF Full-Text \(296 KB\)\]](#) [IEEE JNL](#)

6 Vector geometry for computer graphics

Miller, J.R.;

Computer Graphics and Applications, IEEE , Volume: 19 , Issue: 3 , May-June

Pages:66 - 73

[\[Abstract\]](#) [\[PDF Full-Text \(176 KB\)\]](#) [IEEE JNL](#)

7 Applications of vector geometry for robustness and speed

Miller, J.R.;

Computer Graphics and Applications, IEEE , Volume: 19 , Issue: 4 , July-Aug.

Pages:68 - 73

[\[Abstract\]](#) [\[PDF Full-Text \(144 KB\)\]](#) [IEEE JNL](#)

8 Hybrid vector quantization for multiresolution image coding

Rinaldo, R.; Calvagno, G.;

Image Processing, IEEE Transactions on , Volume: 6 , Issue: 5 , May 1997

Pages:753 - 758

[\[Abstract\]](#) [\[PDF Full-Text \(312 KB\)\]](#) [IEEE JNL](#)

9 Three-dimensional subband coding of video

Podilchuk, C.I.; Jayant, N.S.; Farvardin, N.;

Image Processing, IEEE Transactions on , Volume: 4 , Issue: 2 , Feb. 1995

Pages:125 - 139

[\[Abstract\]](#) [\[PDF Full-Text \(1612 KB\)\]](#) [IEEE JNL](#)

10 Extending the feature vector for automatic face recognition

Jia, X.; Nixon, M.S.;

Pattern Analysis and Machine Intelligence, IEEE Transactions on , Volume: 17 , Issue: 12 , Dec. 1995

Pages:1167 - 1176

[\[Abstract\]](#) [\[PDF Full-Text \(1228 KB\)\]](#) [IEEE JNL](#)

11 A breakpoint analysis procedure based on temporal decomposition

Dix, P.J.; Bloothoof, G.;

Speech and Audio Processing, IEEE Transactions on , Volume: 2 , Issue: 1 , Jan. 1994

Pages:9 - 17

[\[Abstract\]](#) [\[PDF Full-Text \(772 KB\)\]](#) IEEE JNL

12 Three dimensional subband video coding with multiscale edge detection

Ashourian, M.; Yusof, Z.M.; Salleh, S.H.S.; Bakar, S.A.R.A.;

TENCON 2000. Proceedings, Volume: 2, 24-27 Sept. 2000

Pages:436 - 441 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(480 KB\)\]](#) IEEE CNF

13 Solving for 3D motion parameters of a rigid body by a vector geometrical approach : Uniqueness and numerical results

Yen, B.; Huang, T.;

Acoustics, Speech, and Signal Processing, IEEE International Conference on ICASSP '84., Volume: 9, Mar 1984

Pages:267 - 270

[\[Abstract\]](#) [\[PDF Full-Text \(144 KB\)\]](#) IEEE CNF

14 Performance measures for estimating vector systems

Nehorai, A.; Hawkes, M.;

Acoustics, Speech, and Signal Processing, 1999. ICASSP '99. Proceedings., 1999 IEEE International Conference on, Volume: 4, 15-19 March 1999

Pages:1829 - 1832 vol.4

[\[Abstract\]](#) [\[PDF Full-Text \(288 KB\)\]](#) IEEE CNF

15 Low-bit rate subband video coding

Podilchuk, C.;

Image Processing, 1994. Proceedings. ICIP-94., IEEE International Conference, Volume: 3, 13-16 Nov. 1994

Pages:280 - 284 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(372 KB\)\]](#) IEEE CNF

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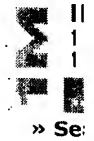
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- ☒ Classification codes A: Physics, 7
- ☒ Classification codes A: Physics, 8
- ☒ Classification codes A: Physics, 9
- ☒ Classification codes B: Electrical & Electronics, 0-5
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